Code:	QI853
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Name: Introdução à Cristalografia

Name in English: Introduction to Crystallography

Name in Spanish: Introducción a la Cristalografía

Subject type: Weekly

Approval Type: Grade and frequency

Characteristic: Regular

Frequency: 75%

Period Type / Offering period: Semestral / All periods

Requires Final Exam: Yes

Vectors									
Т	L	Р	0	PE	OE	SL	WEEKS	CREDITS	
2	-	-	-	-	-	2	15	2	
Occurre	nce on cu	irriculum:							

Pre requirement: QI145 or QI146

**Summary:** Crystals and crystalline structures. Crystalline lattices and spatial symmetry. Crystalline systems. Diffraction in crystals: X-rays, neutrons and electrons. Introduction to the determination of crystalline structure. Examples of minerals, ionic and molecular compounds.

## Program:

- Cell units and lattices and the diffraction experiment; reciprocal space and structural factors.

- Crystal symmetry; symmetry involving translation; crystalline systems and spatial groups.

- Experimental methods: processes and methods of crystallization; data collection for single crystals and polycrystalline samples. X-Rays, neutrons and electrons diffractions.

- Refinement of structures; Patterson and direct methods; minimum squares method. Disorder. Anomalous dispersion.

- Crystallographic databases.

## **Basic Bibliography**

1) HAMMOND, C. **The basics of crystallography and diffraction.** 3rd ed. Oxford, N.Y.: Oxford University Press, 2009. 432p.

2) MASSA, W. Crystal structure determination. 2nd ed. Berlin: Springer, 2004. 210p.

3) CLEGG, W. Crystal structure determination. Oxford: Oxford University Press, 1998. 84p.

## Supplementary Bibliography

1) CLEGG, W. (Ed.). **Crystal structure analysis: principles and practice.** 2nd ed. Oxford, N.Y.: Oxford University Press, 2009. 387p

2) GLUSKER, J. P. Crystal structure analysis for chemists and biologists. New York, N.Y.: VCH, 1994. 854p.

3) PECHARSKY, V. K. Fundamentals of powder diffraction and structural characterization of materials. 2nd ed. New York: Springer, 2009. 741p.

4) LADD, M. F. C. **Structure determination by X-ray crystallography.** 4th ed. New York, NY: Kluwer/Plenum, 2003. 819p.

5) RISSANEN, K. **Advanced X-Ray Crystallography.** Berlin, Heidelberg: Springer Berlin Heidelberg, 2012. (Topics in Current Chemistry; 315). E-book.